

<b>FORM PTO-1449 (SUBSTITUTE)</b> U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  <b>INFORMATION DISCLOSURE          STATEMENT-BY-APPLICANT</b> (37 CFR 1.98(b))				Attorney Docket No.: MUH-12757 Appl. No.: _____  Applicant: MATTHIAS KROENKE ET AL.  Filing Date: September 23, 2003 Group Art Unit: _____			
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EXAMINER INITIALS	PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
gm	A	5,536,672	7/16/96	Miller et al.		
gm	B	5,932,907	8/3/99	Grill et al.		
gm	C	2002/0185683 A1	12/12/02	Yamazaki et al.		
gm	D	2002/0070404 A1	6/13/02	Bruchhaus et al.		
	E					
	F					
	G					
	H					
	I					

  

FOREIGN PATENT DOCUMENT							
DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO		
gm J 100 14 315 A1	10/5/00	Germany					
gm K 00/39842	7/6/00	WIPO					
gm L 00/49660	8/24/00	WIPO					
gm M 99/28972	6/10/99	WIPO					
gm N 98/15012	4/9/98	WIPO					

  

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)	
gm	Heintze, M. et al.: "Oxygen Impurity Effects on the Formation of Thin Titanium Silicide Films by Rapid Thermal Annealing", J. Appl. Phys., Vol. 23, 1990, pp. 1076-1081;
gm	Wee, A. et al.: "Investigation of Titanium Silicide Formation Using Secondary Ion Mass Spectrometry", Mat. Res. Soc. Symp. Proc., Vol. 342, April, 4 1994, pp. 117-122

  

EXAMINER <i>Quinn M. Kennedy</i>	DATE CONSIDERED <i>May 12, 2004</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	